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<b>FORM PTO-1449</b>		Attorney Docket: 1232-4421US1	Divisional of Serial No.: 09/025,409
<b>INFORMATION DISCLOSURE CITATION</b>		Applicant: Uehara et al.	
		Filing Date: 9/19/00	Group Art Unit: UNKNOWN

#### U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
K-CC	AA	5,593,537	1/14/97	Cote et al.	156	636.1	—
K-CC	AB	4,736,760	4/12/88	Coberly et al.	134	134	—
K-CC	AC	4,804,007	2/14/89	Bran	134	184	—
K-CC	AD	5,593,505	2/14/97	Erk et al.	134	1.3	—
K-CC	AE	3,964,957	6/22/76	Walsh	156	345	—
K-CC	AF	4,325,394	4/20/82	Reams	134	141	—
K-CC	AG	4,854,337	8/8/89	Bunkenburg et al.	134	184	—
K-CC	AH	5,286,657	2/15/94	Bran	437	9	—
K-CC	AI	5,327,921	7/12/94	Mokuo et al.	134	182	—
K-CC	AJ	5,791,357	8/11/98	Hasegawa	134	137	—
K-CC	AK	5,816,274	10/6/98	Bartram et al.	134	140	—
K-CC	AL	5,672,212	9/30/97	Manos	134	1.3	—
K-CC	AM	5,727,582	3/17/98	Terui	134	140	—
Q	AN						
	AO						

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K-CC	AP	8-117702A	5/1996	Japan	—	—	Abstract
K-CC	AQ	07-142439A	6/1995	Japan	—	—	Abstract
K-CC	AR	5-243203	9/21/93	Japan	—	—	Abstract
K-CC	AS	8-293478	11/5/96	Japan	—	—	Abstract
K-CC	AT	53-144265	12/15/78	Japan	—	—	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No

abstract

#### OTHER DOCUMENTS (Including Author, Title, Date, etc.)

	AU	
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	AW	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

Kih-cha chen

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<b>U.S. PATENT DOCUMENTS</b>							
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<b>FOREIGN PATENT DOCUMENTS</b>							
K-cc	AP	62-283632	9/12/87	Japan	—	—	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
K-cc	AQ	1-187931	7/27/89	Japan	—	—	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
K-cc	AR	1-304733	812/89	Japan	—	—	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
K-cc	AS	3-62925	3/19/91	Japan	—	—	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
K-cc	AT	3-257826	11/18/91	Japan	—	—	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No

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<b>OTHER DOCUMENTS (Including Author, Title, Date, etc.)</b>							
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<i>Kun-chen Chen</i> 01-04-02							



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K-cc	AP	9-038079	2/21/97	Japan	—	—	<input checked="" type="checkbox"/> Yes <input type="checkbox"/> No
K-cc	AQ	9-038080	2/21/97	Japan	—	—	<input checked="" type="checkbox"/> Yes <input type="checkbox"/> No
K-cc	AR	0 319 806	6/14/89	Europe	—	—	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
	AS						<input type="checkbox"/> Yes <input type="checkbox"/> No
	AT						<input type="checkbox"/> Yes <input type="checkbox"/> No

**OTHER DOCUMENTS (Including Author, Title, Date, etc.)**

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<b>INFORMATION DISCLOSURE CITATION</b> <b>FORM PTO-1449</b>		Attorney Docket:	Divisional of Serial No.:
		1232-4421US1	09/664,715
		Applicant:	
		Uehara et al..	
		Filing Date:	Group Art Unit:
		9/19/00	UNKNOWN

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Sub-Class	Filing Date
AA	5,327,921	7/12/94	Mokuo et al.	134	182	
AB	4,191,295	3/4/1980	Tams, III.	211	41	
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AD						SEP 25 2001
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**FOREIGN PATENT DOCUMENTS**

Examiner Initial	Patent No.	Date	Country	Class	Sub-cals	English Translation
AK	EP 740331	10/30/96	Europe			Yes
AL	EP 319806	6/14/89	Europe			Yes
AM	EP 694957	1/31/96	Europe			Yes
AN	EP 554795	8/11/93	Europe			Yes
AO	EP 3257826	11/18/91	Europe			Abstract
AP	EP 1304733	12/8/89	Europe			Abstract
AQ	EP 8316182	11/29/96	Europe			Abstract
AR	FR 2626261	7/28/89	France			Abstract
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AU	K. Sakaguchi, Et Al., "Extremely High Selective Etching Of Porous Si For Single Etch-Stop Bond-And-Etch-Back Silicon-on-Insulator, <i>Jpn. J. Appl. Phys.</i> , Vol. 34 (1995) pp.842-847, Part 1, No. 2B, February 1995
AV	Communication dated August 6, 2001 in EP 98102897 and Partial European Search Report
AW	

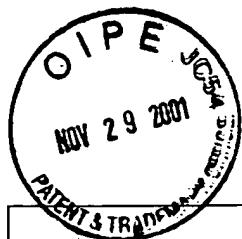
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( Replaced by Paper No.4 IDS .

( see Paper No. 4 IDS (Nov. 29, 2001)

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FORM PTO-1449		Attorney Docket: 1232-4421US1	Divisional of Serial No.: 09/664,715
<u>INFORMATION DISCLOSURE CITATION</u>		Applicant: Uehara et al.	
		Filing Date: 9/19/2000	Group Art Unit: 1746

**U.S. PATENT DOCUMENTS**

Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
K-cc	AA	5,327,921	7/12/94	Mokuo et al.	134	182	—
K-cc	AB	4,191,295	3/4/1980	Tams, III.	211	41	—
	AC						
	AD						
	AE						NOV 30 2001
	AF						
	AG						
	AJ						TC 1700

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K-cc	AK	EP 740331	10/30/96	Europe	—	—	Yes
K-cc	AL	EP 319806	6/14/89	Europe	—	—	Yes
K-cc	AM	EP 694957	1/31/96	Europe	—	—	Yes
K-cc	AN	EP 554795	8/11/93	Europe	—	—	Yes
K-cc	AO	JP 3-257826	11/18/91	Japan	—	—	Abstract
K-cc	AP	JP 1-304733	12/8/89	Japan	—	—	Abstract
K-cc	AQ	JP 8-316182	11/29/96	Japan	—	—	Abstract
K-cc	AR	FR 2626261	7/28/89	France	—	—	Abstract
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K-cc	AU	K. Sakaguchi, Et Al., "Extremely High Selective Etching Of Porous Si For Single Etch-Stop Bond-And-Etch-Back Silicon-on-Insulator, <i>Jpn. J. Appl. Phys.</i> , Vol. 34 (1995) pp.842-847, Part 1, No. 2B, February 1995
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K-CC	AB	2,702,260	2/15/1955	F. Massa	—	—	—
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	AM						
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## OTHER DOCUMENTS (Including Author, Title, Date, etc.)

K-CC	AU	European Patent Office's Communication dated October 15, 2001, in EP 98102897 and a European Search Report.
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